

MS Thesis

Design and Implementation of High-Speed CMOS Clock and Data Recovery Circuit for Optical Interconnection Applications

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Dec. 20, 2002

Semiconductor System Laboratory,

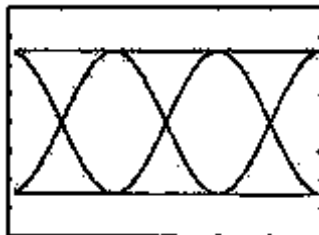
**Department of Electrical Engineering and Computer Science,
Korea Advanced Institute of Science and Technology (KAIST)**

Outline

- Introduction
- Motivation
- Problem Definition
- Proposed 1/8-Rate CDR
- Building Blocks
- Measurement Results
- Conclusion & Further Works

Introduction

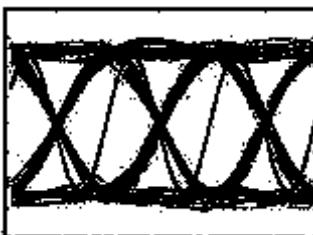
Optical Input Data



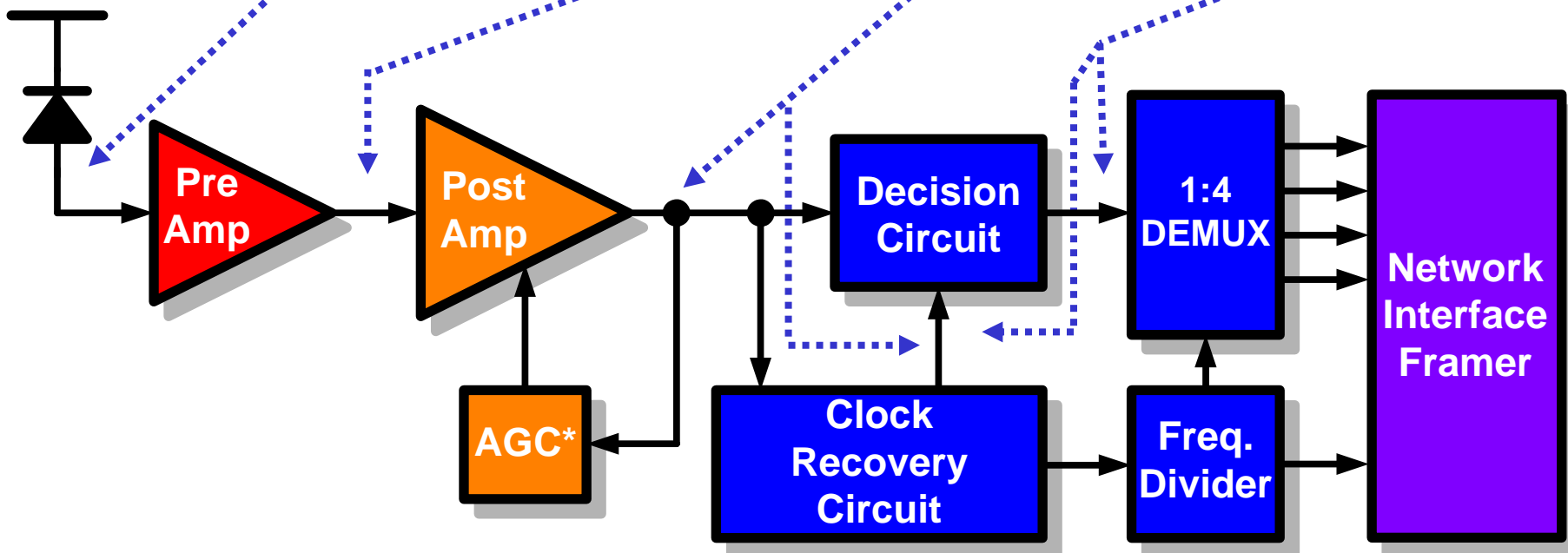
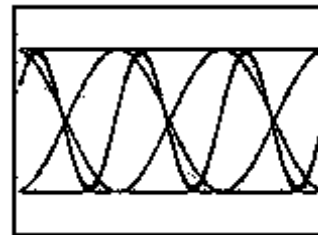
Noise Corrupted Data



Boosted Data
Recovered Clock



Retimed Data
Recovered Clock



* AGC : Automatic Gain Control

Motivation

Long-Haul Applications
(SONET, Gigabit Ethernet)



III-V, Si Bipolar, SiGe HBT

- 😊 Very high-speed
- 😊 Inherently low noise
- 😞 High cost
- 😞 High power consumption
- 😞 Not compatible with other technologies

✓ Short-Haul Applications
(Backplane, Chip-to-Chip)



✓ CMOS

- 😊 Low cost
- 😊 High level of integration
- 😊 Low power consumption
- 😞 Less speed
- 😞 High noise



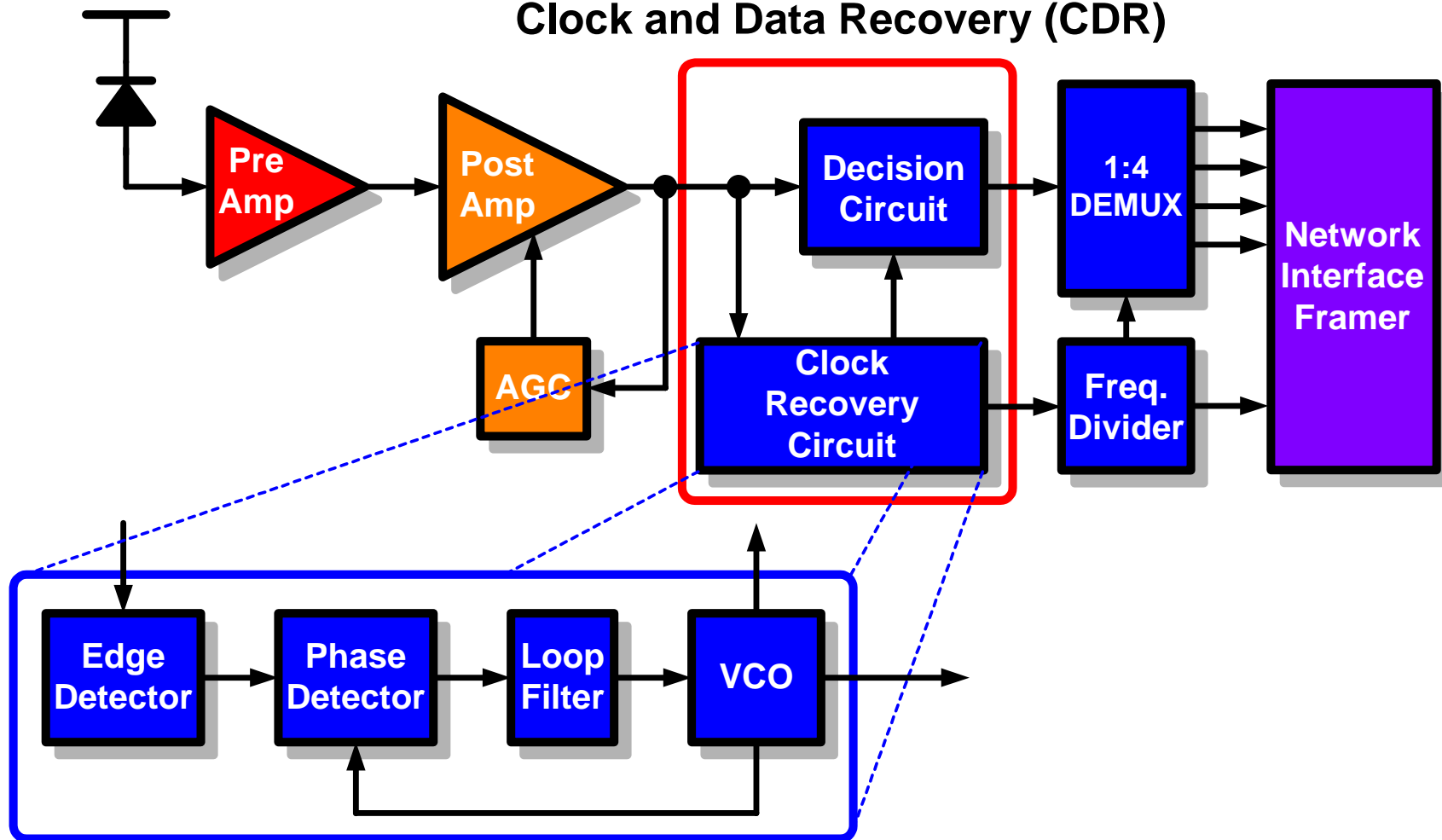
The Solution is
Novel CDR Architecture and Circuit Techniques
In CMOS !!!

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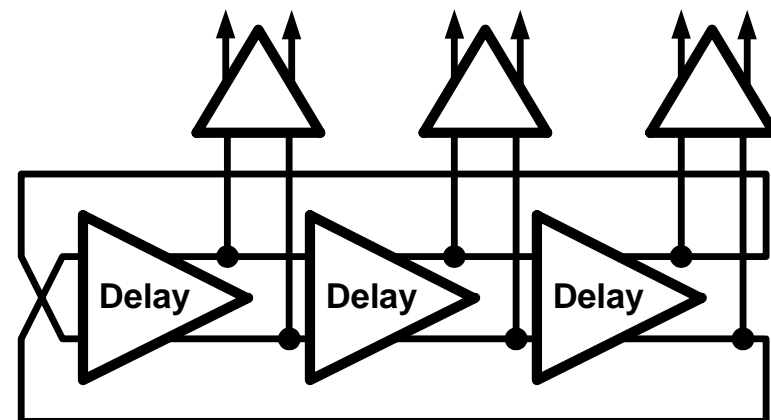
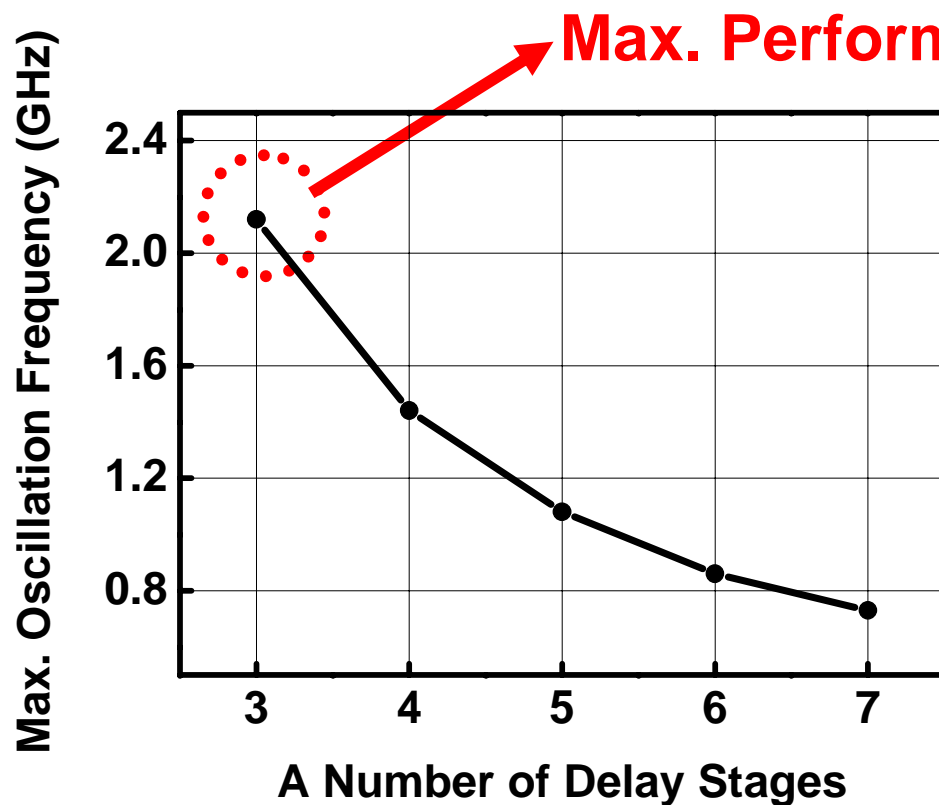
Generic CDR Configuration

Clock and Data Recovery (CDR)



PLL-Based Clock Recovery Circuit

Performance Limitation of 0.25- μm CMOS *

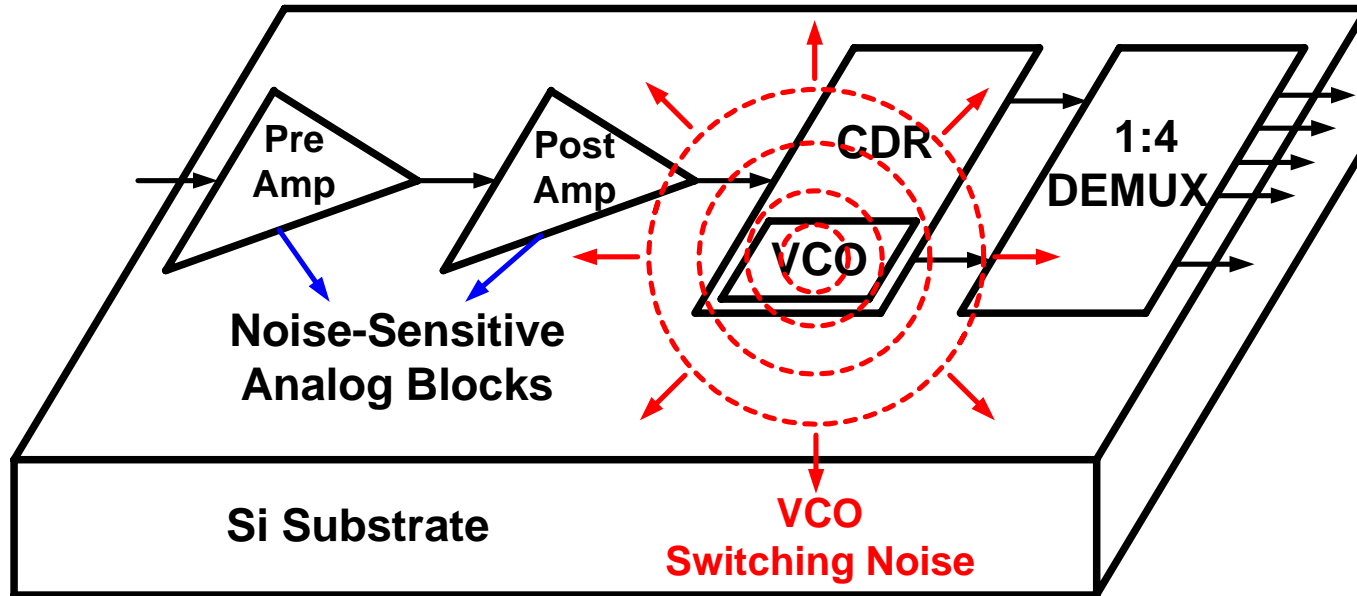


Simple VCO

* M. Fukaiishi, et al., JSSC, Dec. 1998

- Simulation result for 0.25- μm CMOS differential ring oscillators with resistive loads and isolation buffers

Substrate Noise Effect of VCO



$$\text{Substrate noise voltage} \propto \sqrt{f}^*$$

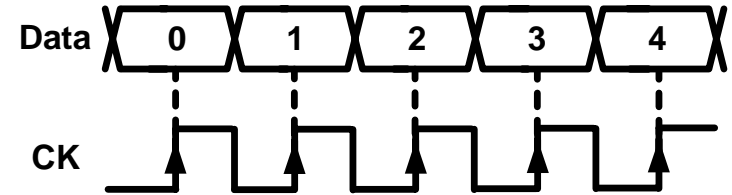
* M. van Heijningen, et al., JSSC, Aug. 2002

Conventional CDR Techniques (1/2)

❑ Full-Rate Clock Technique *

- ☹ Full-rate clock frequency (4GHz)
- ☹ Impossible to design VCO

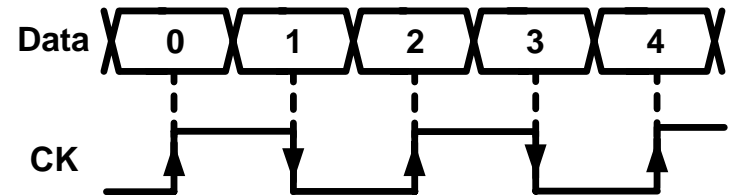
* M. Soyuer, et al., JSSC, Dec. 1993



❑ Half-Rate Clock Technique **

- ☹ Half-rate clock frequency (2GHz)
- ☹ Close to performance limitation
- ☹ Difficult to design VCO

** M. Rau, et al., JSSC, July 1997

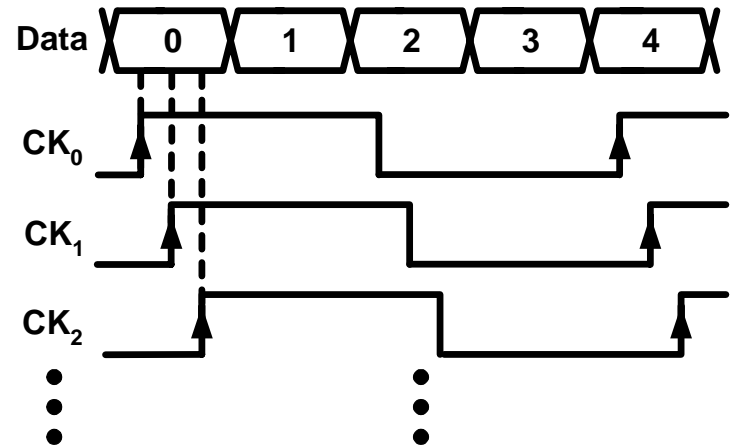


Conventional CDR Techniques (2/2)

❑ Oversampling Technique *

- 😊 Quarter-rate clock frequency (1GHz)
- 😊 Easier to design VCO
- 😞 Highly clock phase resolution
- 😞 Quantization jitter
- 😞 Extra decision logic

* C.-K. Yang, et al., JSSC, May 1998



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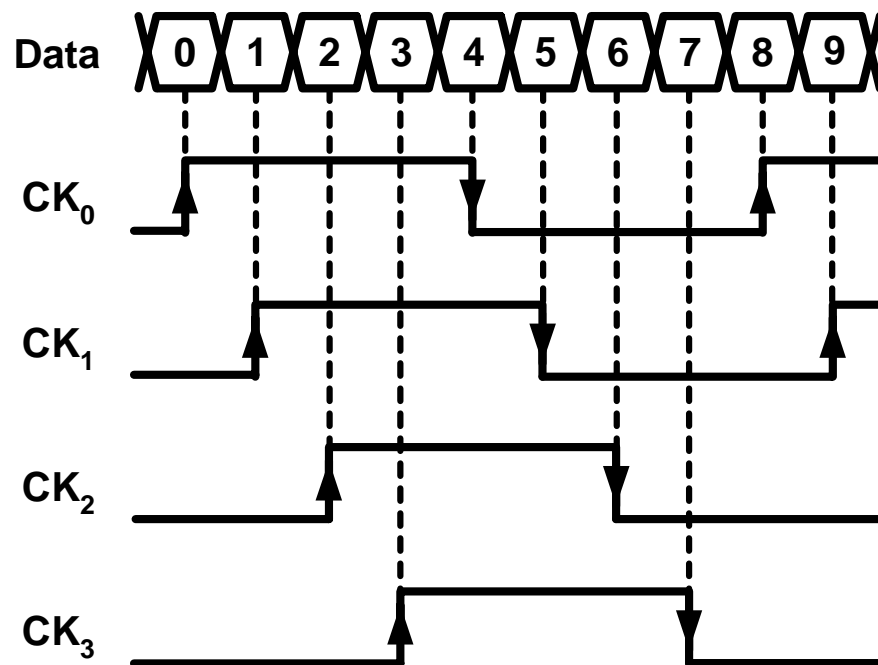
Proposed CDR Technique

□ 1/8-Rate Clock Technique *

- ☺ 1/8-rate clock frequency (0.5GHz)
- ☺ Very easy to design VCO
- ☺ No quantization jitter
- ☺ No extra decision logic
- ☺ Can do 1:4 DEMUX
- ☹ Complex design

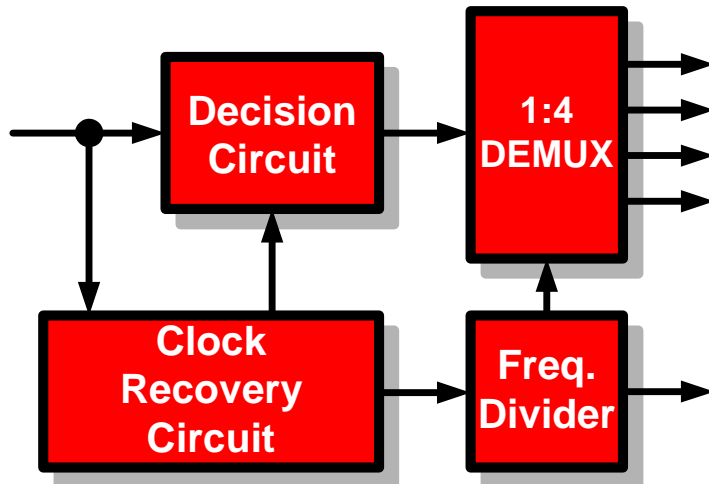
* S.-J. Song, et al., ESSCIRC, Sept. 2002

* S.-J. Song, et al., to be published for JSSC, July 2003



Proposed 1/8-Rate CDR Architecture

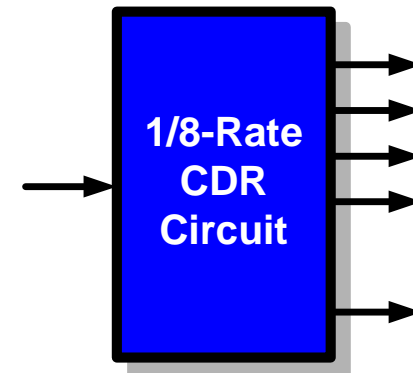
Conventional Full-Rate CDR



Multiple Functional Blocks

Proposed 1/8-Rate CDR

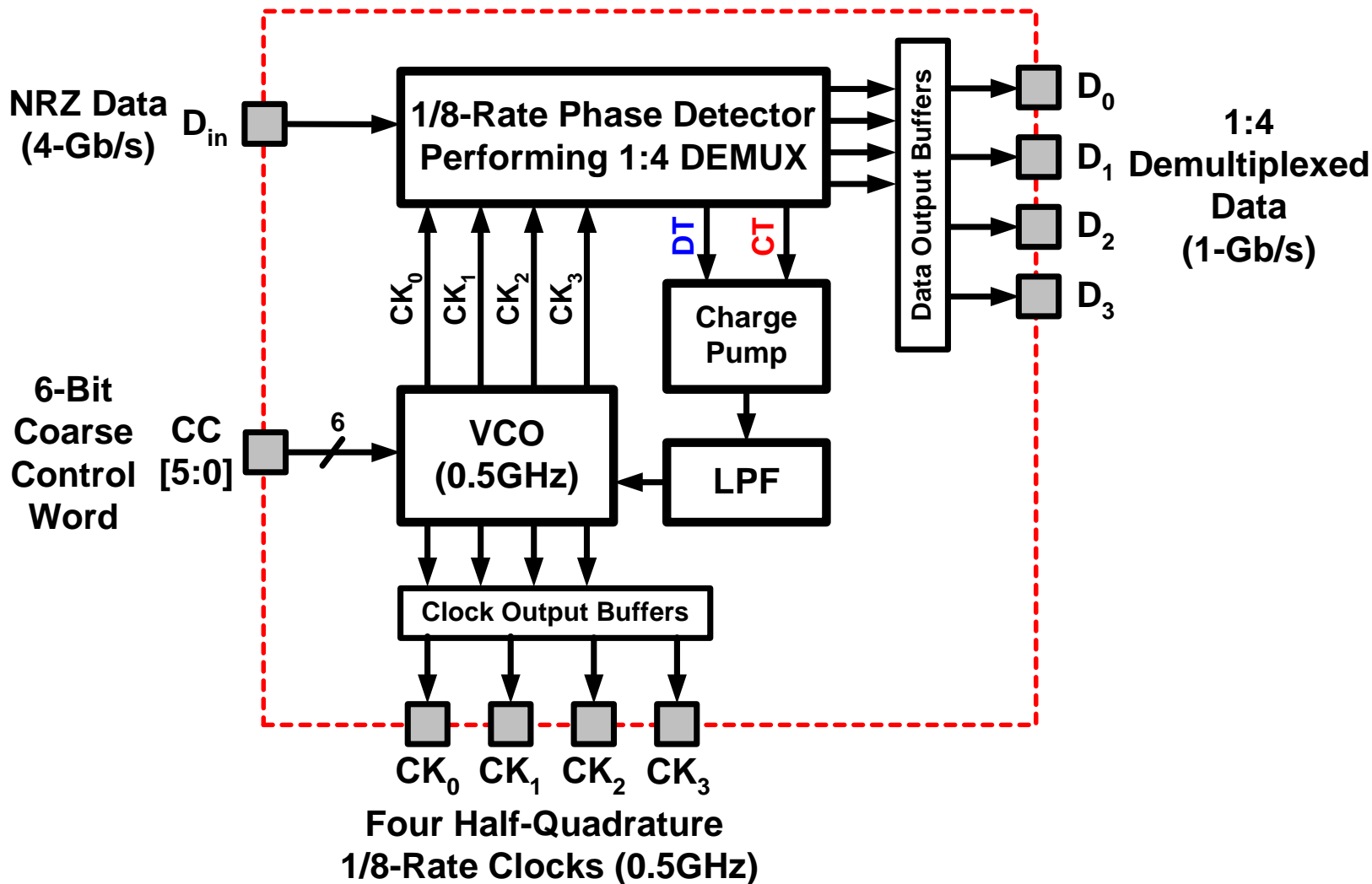
Merging



A Single Functional Block

- Proposed 1/8-rate CDR circuit can achieve higher speed operation, lower power consumption, and smaller area.

Proposed 1/8-Rate CDR Circuit

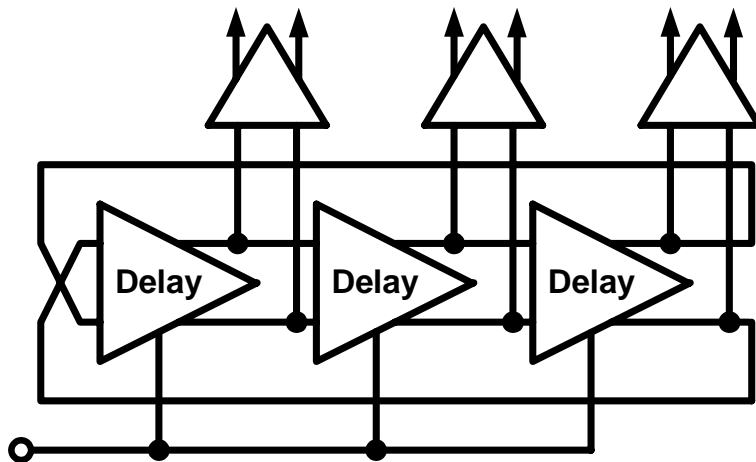


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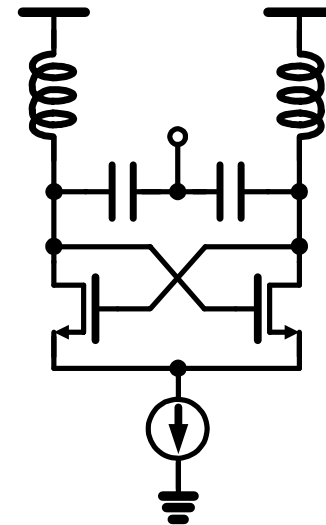
Choice of VCO Configuration

✓ Ring Oscillator



- ☺ Wide tuning range
- ☺ Different phase clock generation
- ☹ Low center frequency
- ☹ Low Q factor
- ☹ High phase noise & jitter

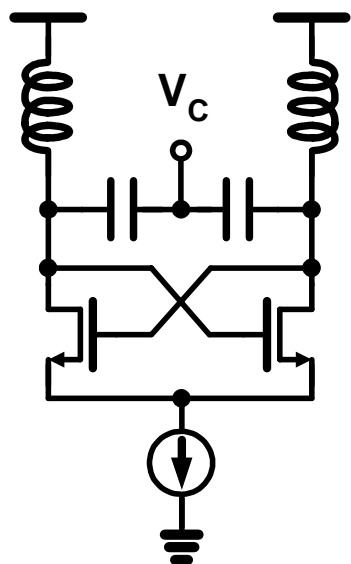
LC Oscillator



- ☺ High center frequency
- ☺ High Q factor
- ☺ Low phase noise & jitter
- ☹ Narrow tuning range
- ☹ Large area

Choice of Inductor Load

Spiral Inductor Load



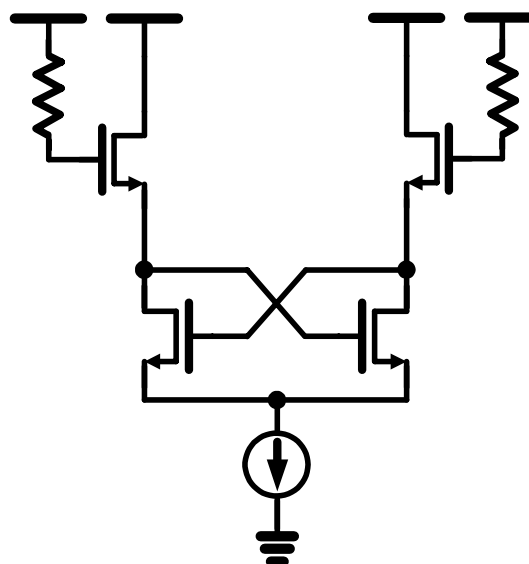
$$C \propto V_c$$

$$\omega_{osc} \propto \frac{1}{\sqrt{LC}}$$

$$\propto \frac{1}{\sqrt{V_c}}$$

- ☹ Low Q factor (3~5)
- ☹ Large area
- ☹ Dependent on process
- ☹ Difficult to design

✓ Active Inductor Load



$$L \propto \frac{1}{g_m}$$

$$\omega_{osc} \propto \frac{1}{\sqrt{LC}}$$

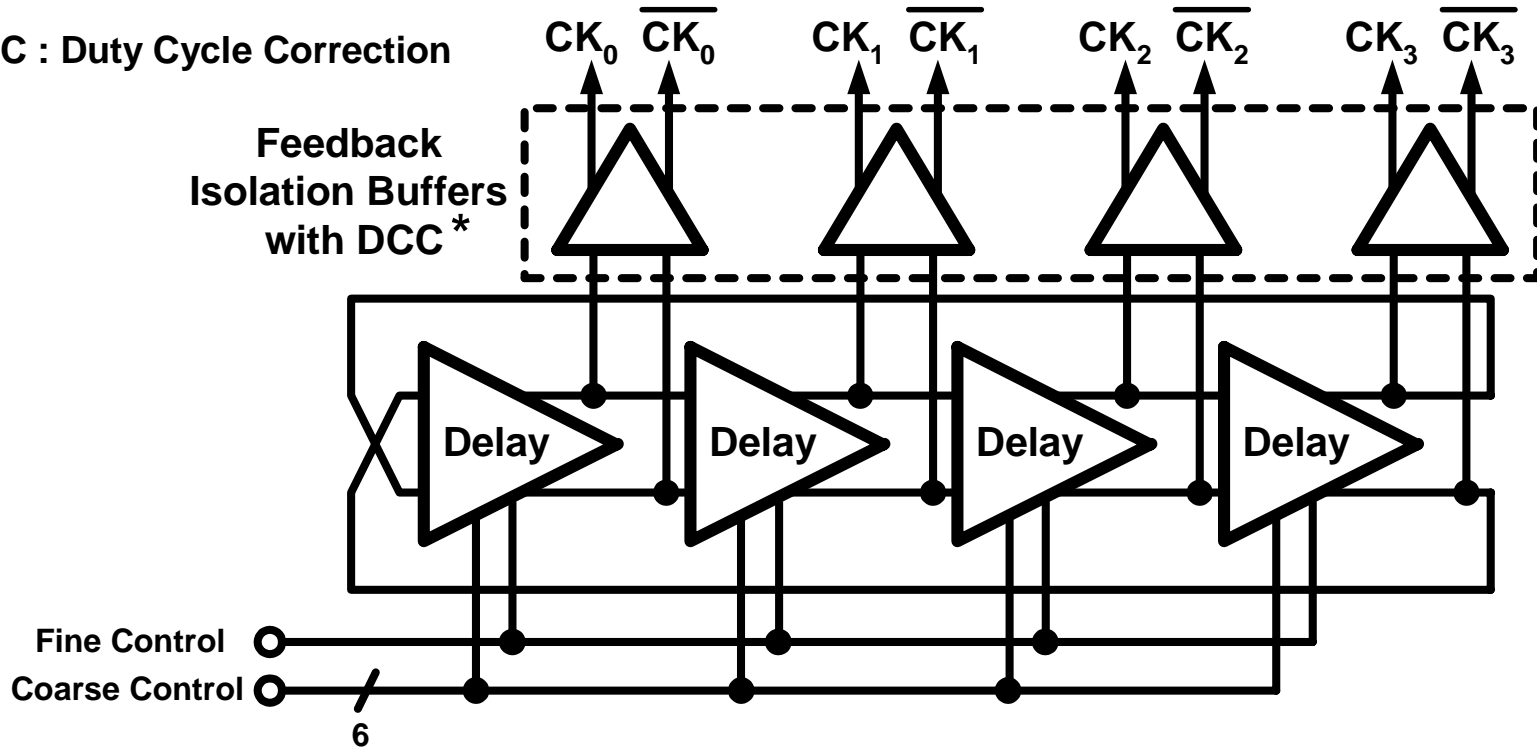
$$\propto \sqrt{g_m}$$

$$\propto \sqrt{\sqrt{I_D}}$$

- ☺ Moderately high Q factor (>>10)
- ☺ Small area
- ☺ Easy to design
- ☹ Noise caused by resistor and MOS

Voltage-Controlled Oscillator

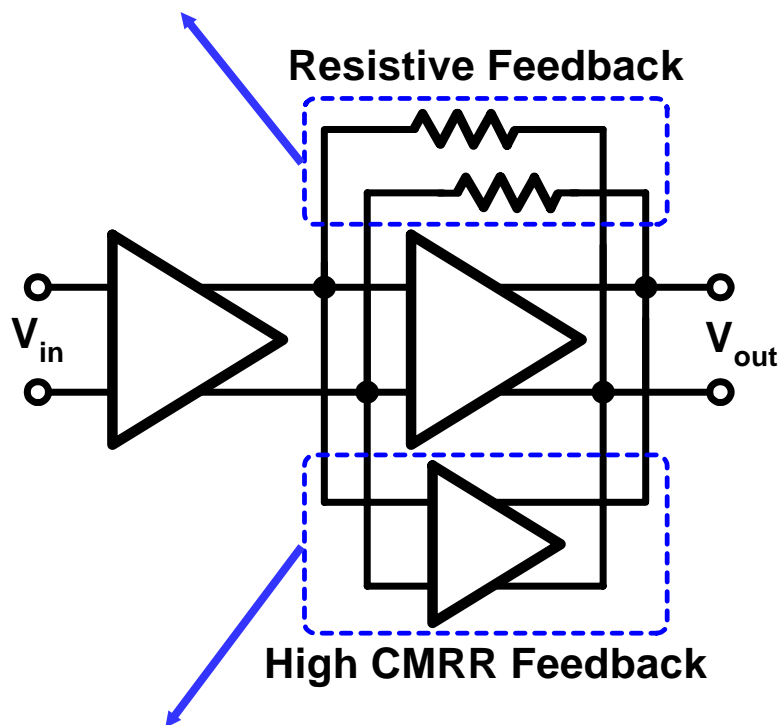
* DCC : Duty Cycle Correction



- Four half-quadrature phase clocks
- Delay stage with active inductor load
- DCC for using both rising and falling edges of clock

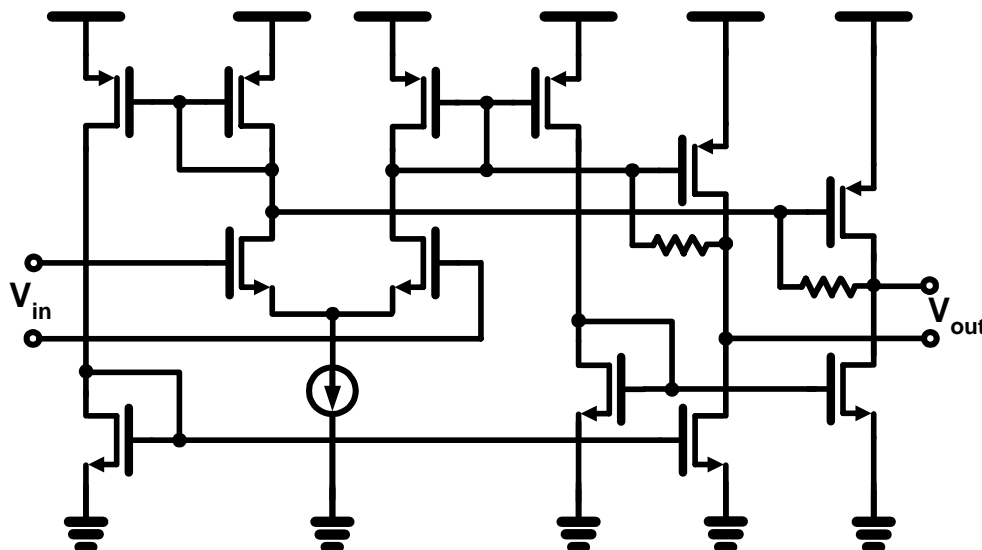
Feedback Isolation Buffer

Bandwidth Extension



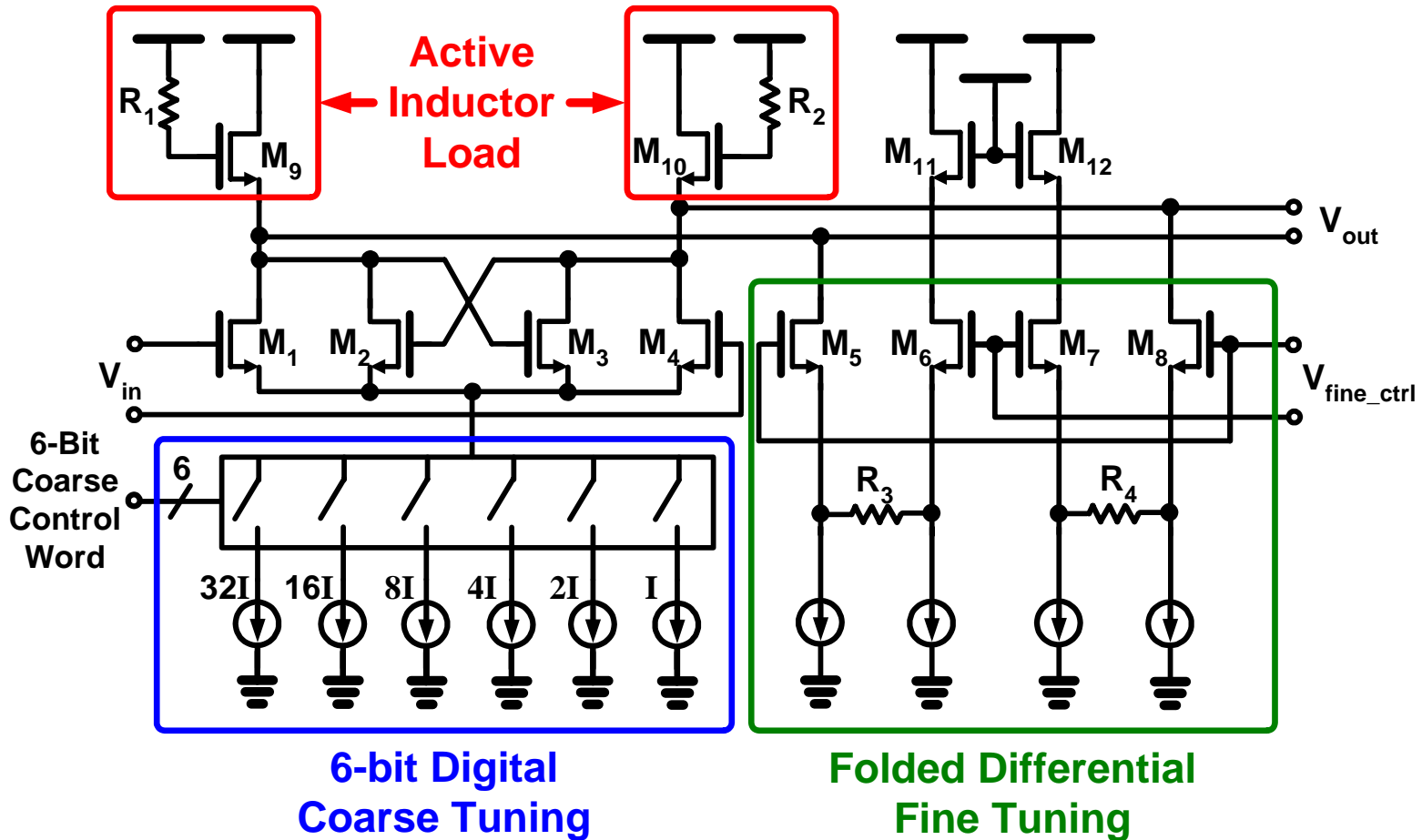
Duty-Cycle Correction

(a) Block Diagram



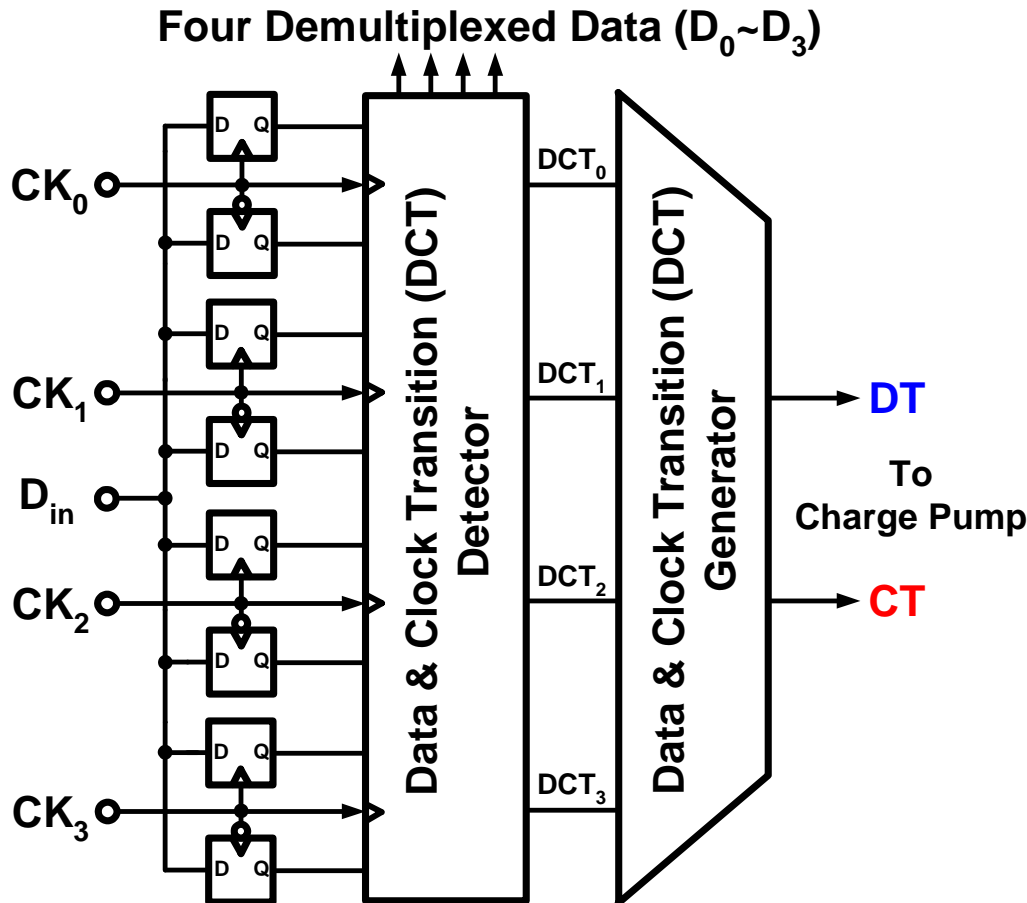
(b) Transistor-Level Implementation

Single Delay Stage of the VCO



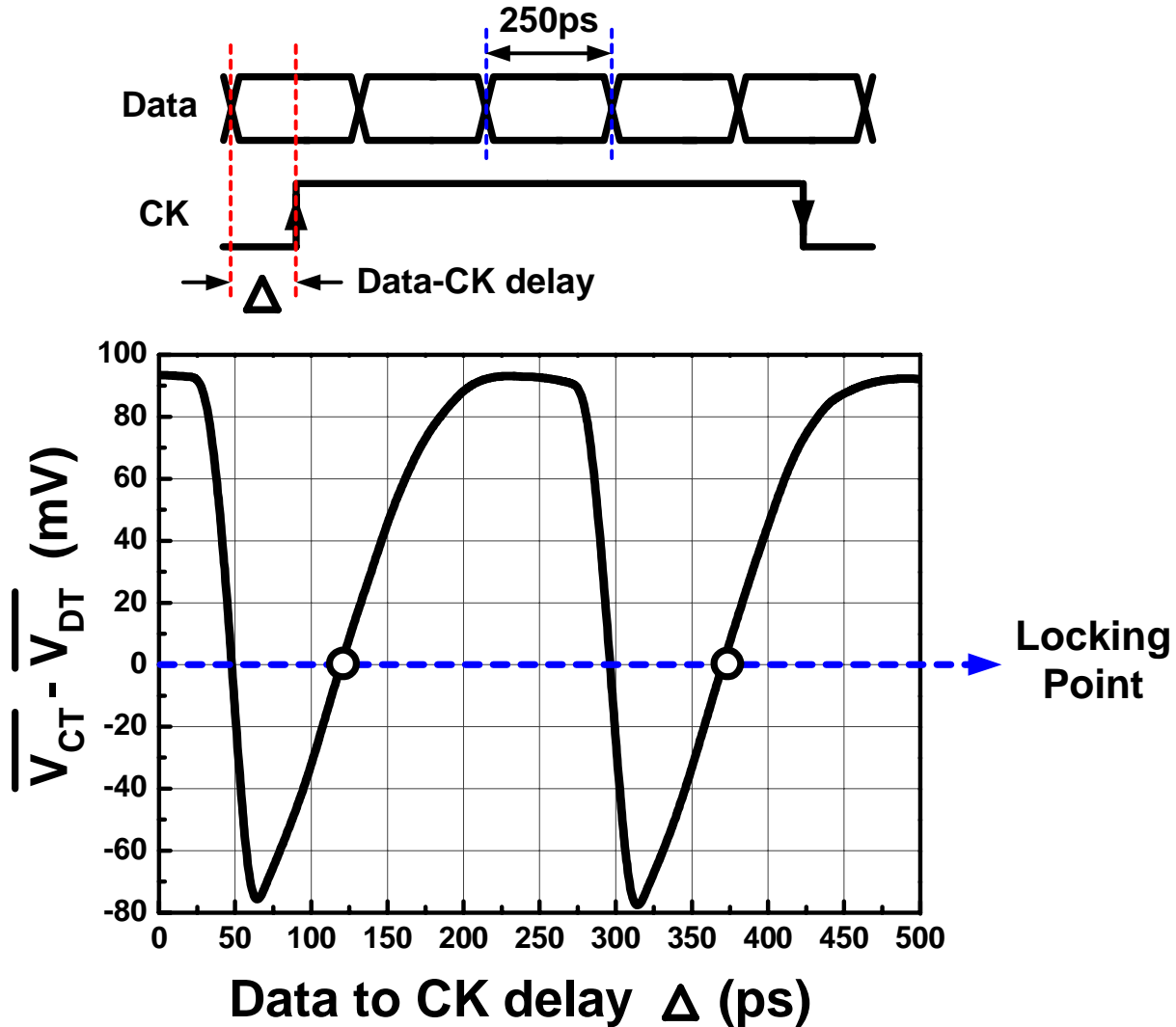
$$\therefore \omega_{osc} = \omega_{FR} + K_{VCO_Fine} V_{fine_ctrl} + K_{VCO_Coarse} N \quad \text{for } N = 0, \dots, 63$$

1/8-Rate Linear Phase Detector



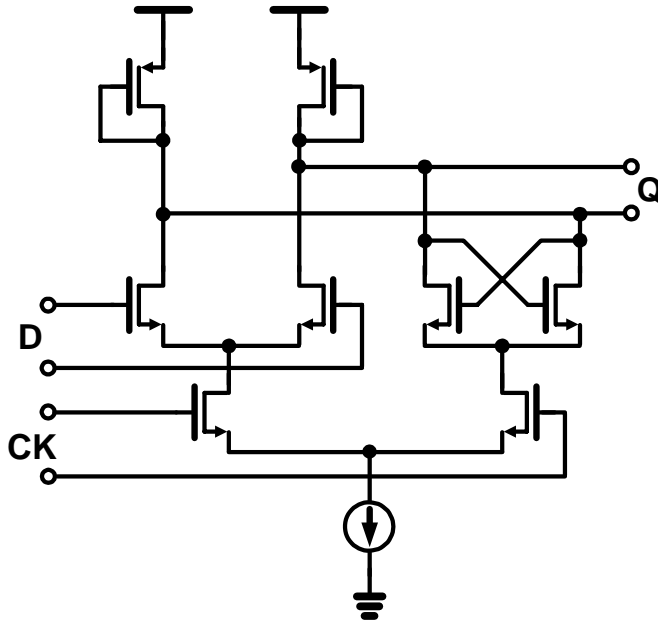
- Three tasks
 - Data Transition Detection
 - Linear phase error detection
 - Data regeneration
- Data demultiplexing
- No systematic offset
- Employing proposed folded current-mode logic family (D-latch, MUX, and XOR)

1/8-Rate Linear PD Characteristic



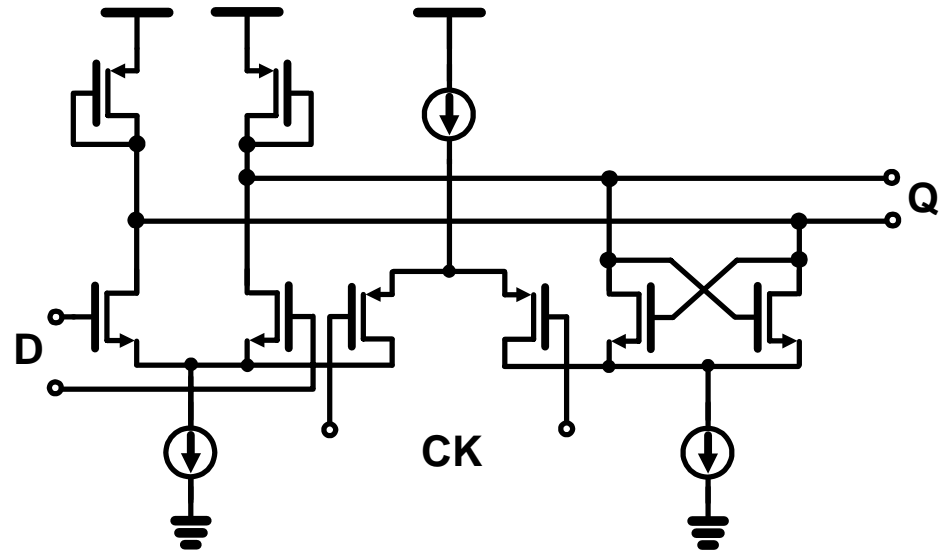
Current-Mode Logic (CML)

Conventional CML D-Latch



- 😊 High speed operation
- 😊 Low power consumption
- 😞 High supply voltage
- 😞 Need for level shifter

Proposed Folded CML D-Latch

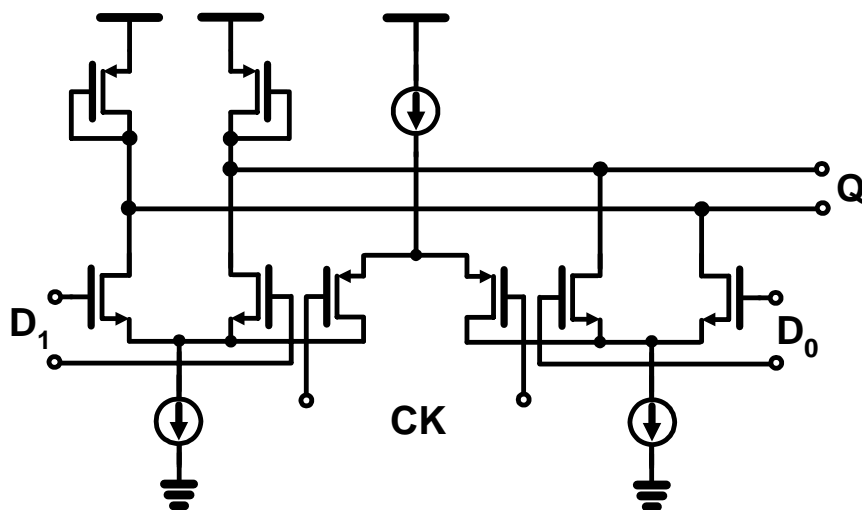


- 😊 Higher speed operation
- 😊 Low supply voltage
- 😊 No need for level shifter
- 😊 Wide input/output range
- 😞 High power consumption
- 😞 Large area

Proposed Folded CML Family *

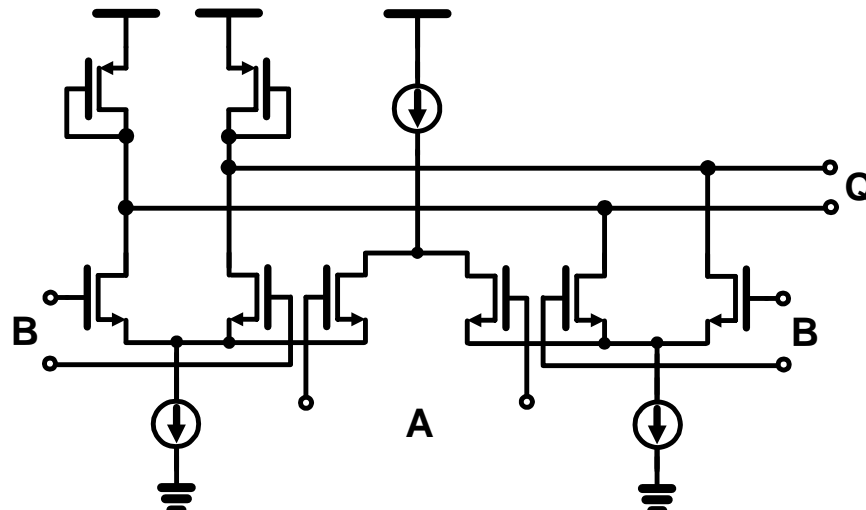
Folded MUX *

$$Q = CK \cdot D_1 + \overline{CK} \cdot D_0$$



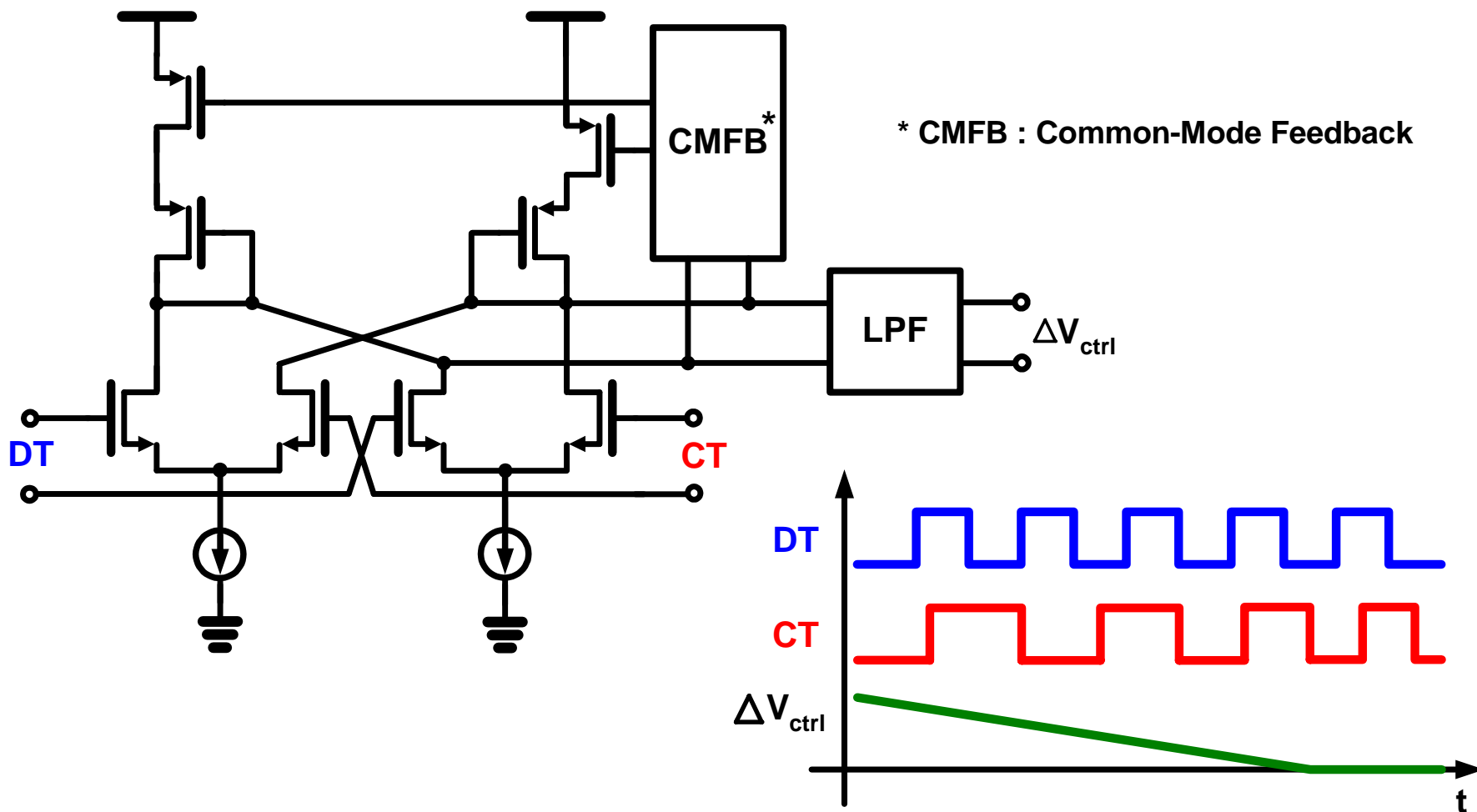
Folded XOR *

$$Q = A \cdot \overline{B} + \overline{A} \cdot B = A \oplus B$$



* S.-J. Song, et al., to be published for JSSC, July 2003

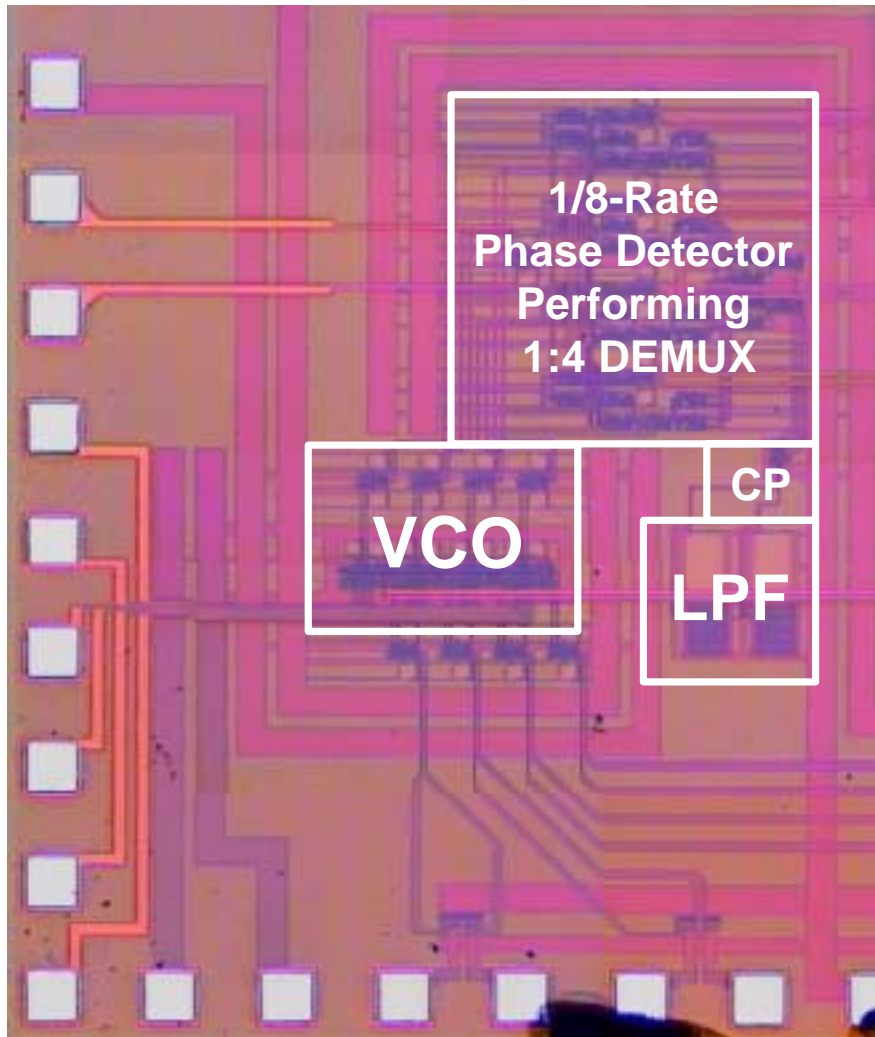
Fully Differential Charge Pump



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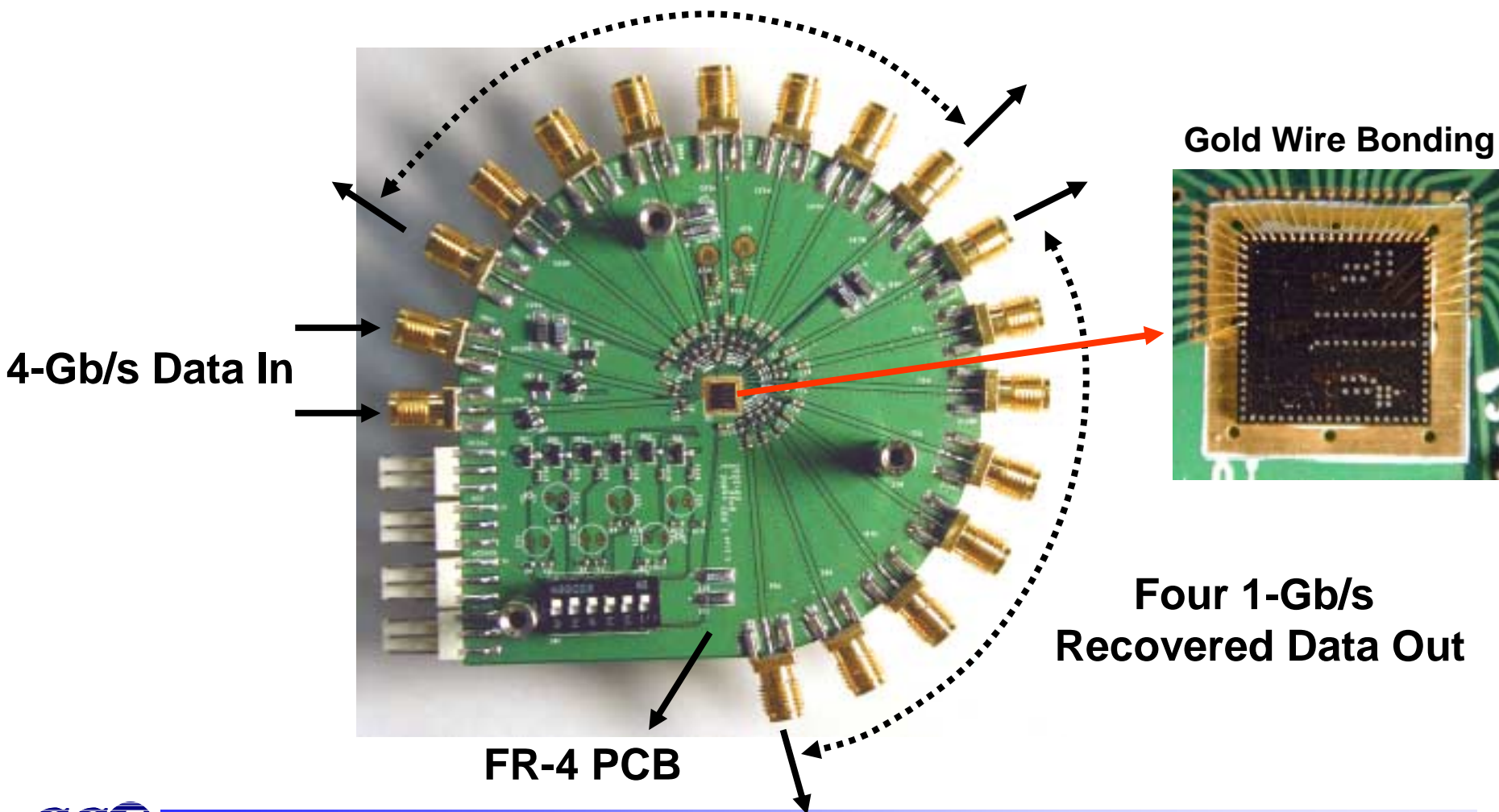
Chip Microphotograph



- ❑ 0.25-μm Standard CMOS
- ❑ 0.9 x 1.0 mm²

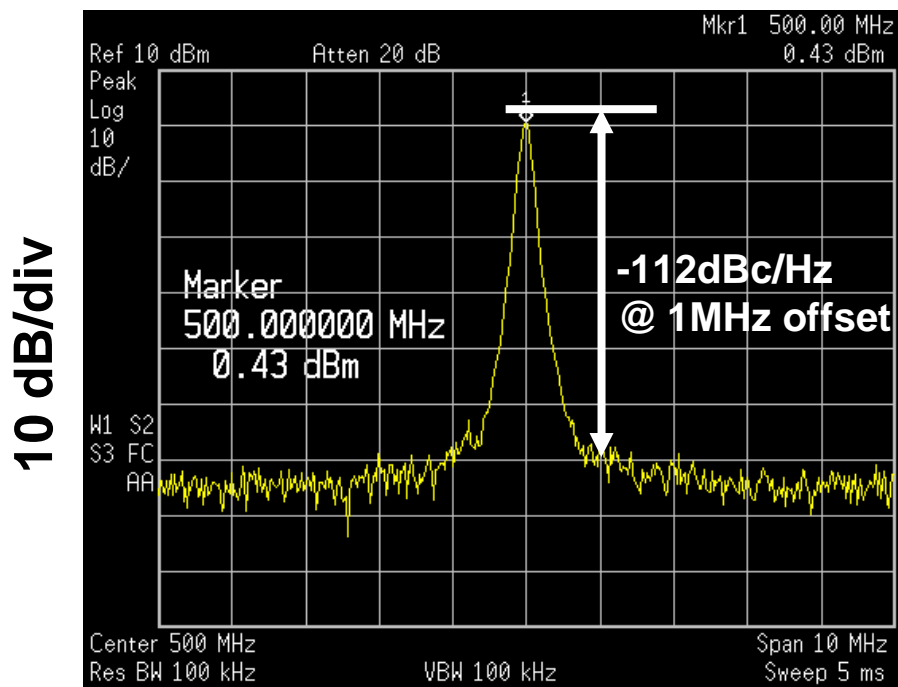
Test Fixture

Four 0.5GHz Recovered Clock Out

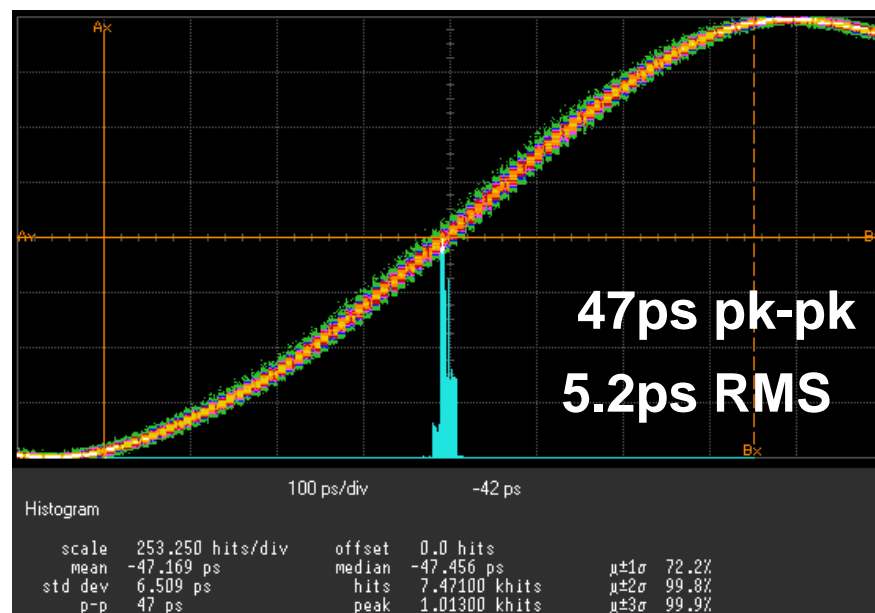


Measured Recovered Clock

□ For $2^{31}-1$ PRBS input data at 4-Gb/s,



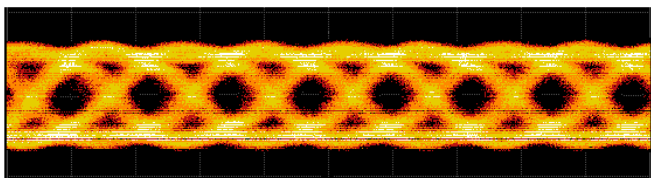
1 MHz/div



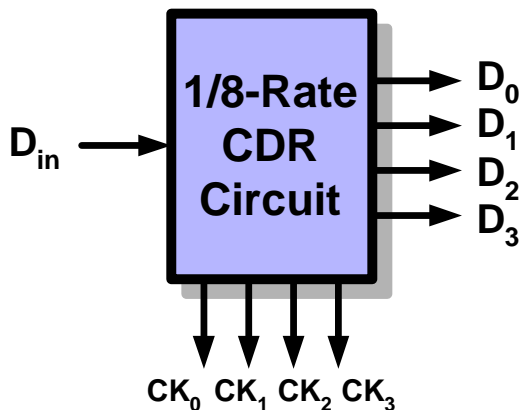
100 ps/div

Measured Eye Diagrams

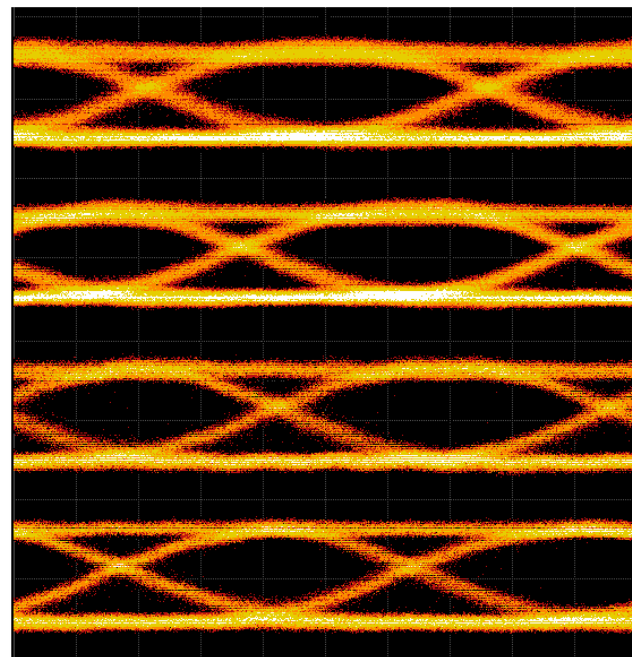
$2^{31}-1$ PRBS Data Input (4-Gb/s)



V: 200 mV/div, H: 200 ps/div

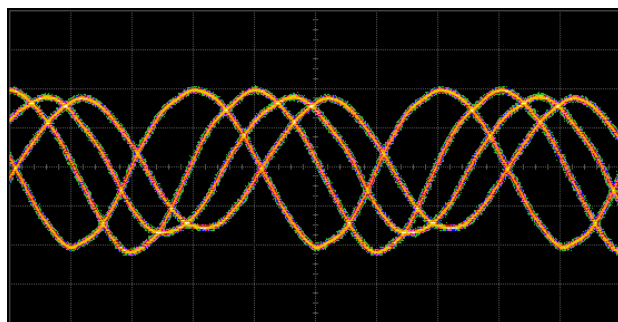


Four Recovered Data Output (1-Gb/s)



V: 200 mV/div, H: 200 ps/div

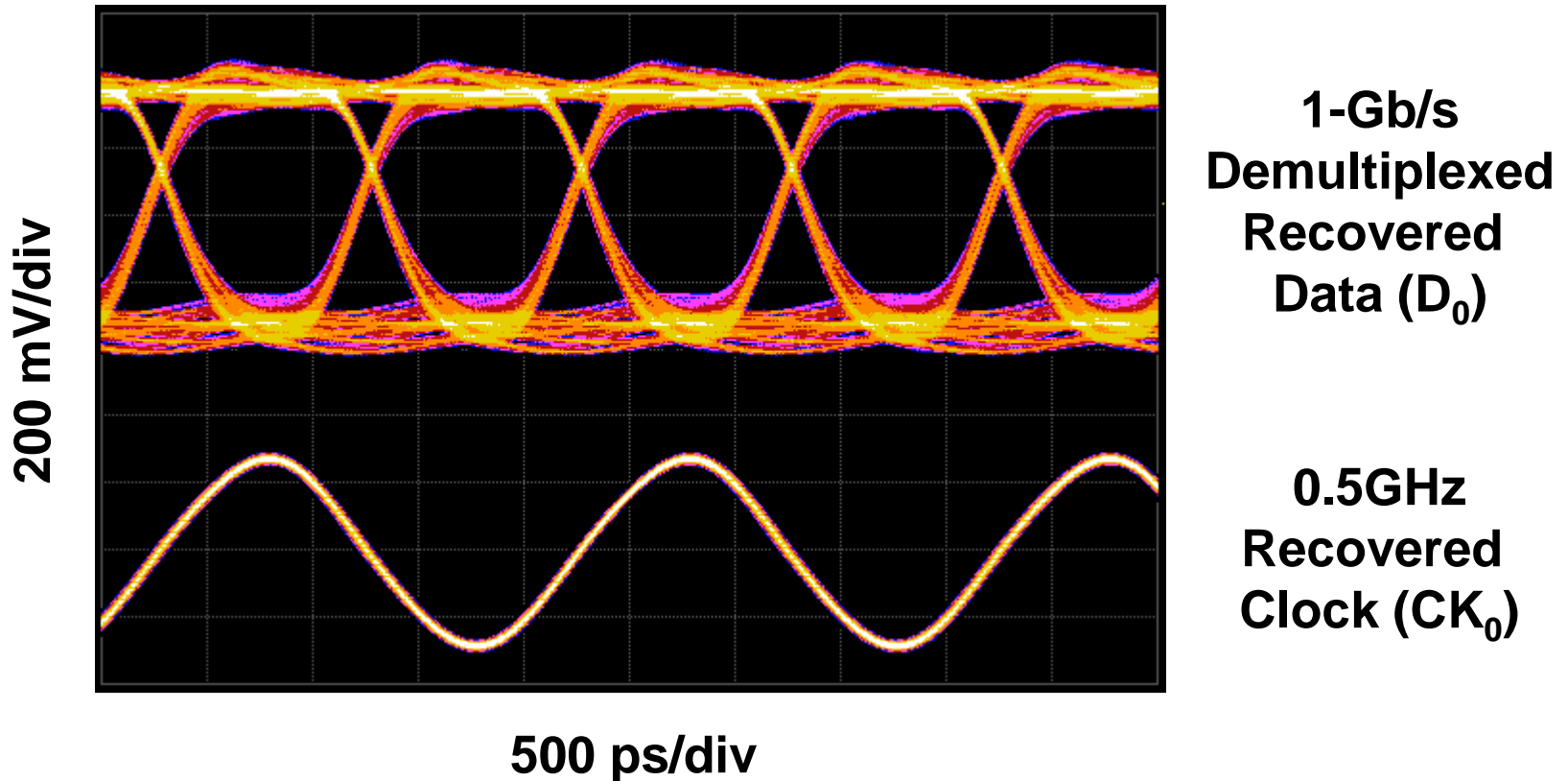
Four Recovered Clock Output (0.5GHz)



V: 200 mV/div, H: 500 ps/div

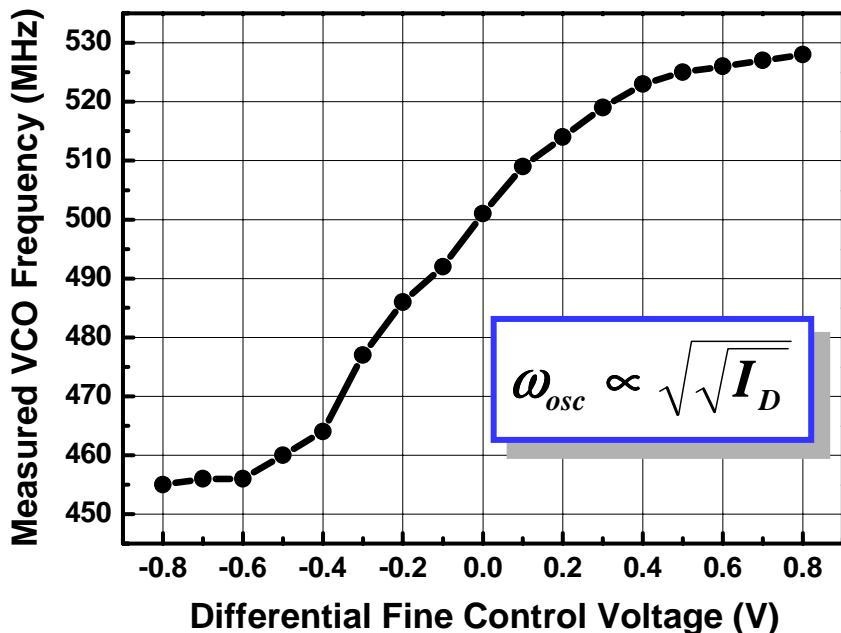
Recovered Clock and Data

- For $2^{31}-1$ PRBS input data at 4-Gb/s,

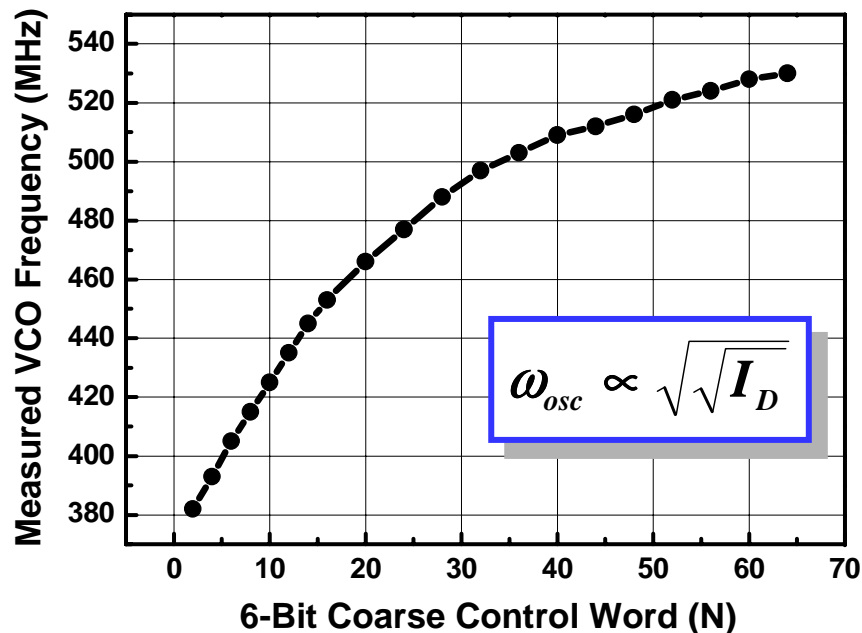


Measured VCO Characteristic

Differential Fine Tuning



6-Bit Digital Coarse Tuning



- $K_{VCO_Fine} = 75 \text{ MHz/V}$
- Fine Tuning Range = 70 MHz (14%)

- $K_{VCO_Coarse} = 2.5 \text{ MHz/Word Step}$
- Coarse Tuning Range = 150 MHz (30%)

$$\therefore \omega_{osc} = \omega_{FR} + K_{VCO_Fine} V_{fine_ctrl} + K_{VCO_Coarse} N \quad \text{for } N = 0, \dots, 63$$

Performance Summary

NRZ Data Rate	4-Gb/s
Recovered Clock	0.5 GHz
Recovered Data	Four 1-Gb/s
Capture Range	16 MHz
VCO Fine Tuning Gain	75 MHz/V
Phase Noise at 1-MHz offset	-112 dBc/Hz
Clock Jitter for $2^{31}-1$ PRBS	5.2 ps RMS
BER for $2^{31}-1$ PRBS	$< 10^{-6}$
Power Dissipation (excluding output buffers)	70 mW
Supply Voltage	2.5 V
Active Area	0.9 x 1.0 mm²
Technology	0.25-μm standard CMOS

Proposed Performance Index

- ❑ From O. T.-C. Chen, et al., JSSC, Jan. 2002,
- ❑ Frequency index in PLL is derived by

$$F^* = \left(\frac{\text{Technology}}{0.35 \mu\text{m}} \right) \cdot \left(\frac{1.8 \text{ V}}{\text{Supply Voltage}} \right) \times F \text{ (MHz)}$$

- ❑ By taking account into power consumption in CDR circuit,
- ❑ Proposed performance index in CDR circuit can be expressed as

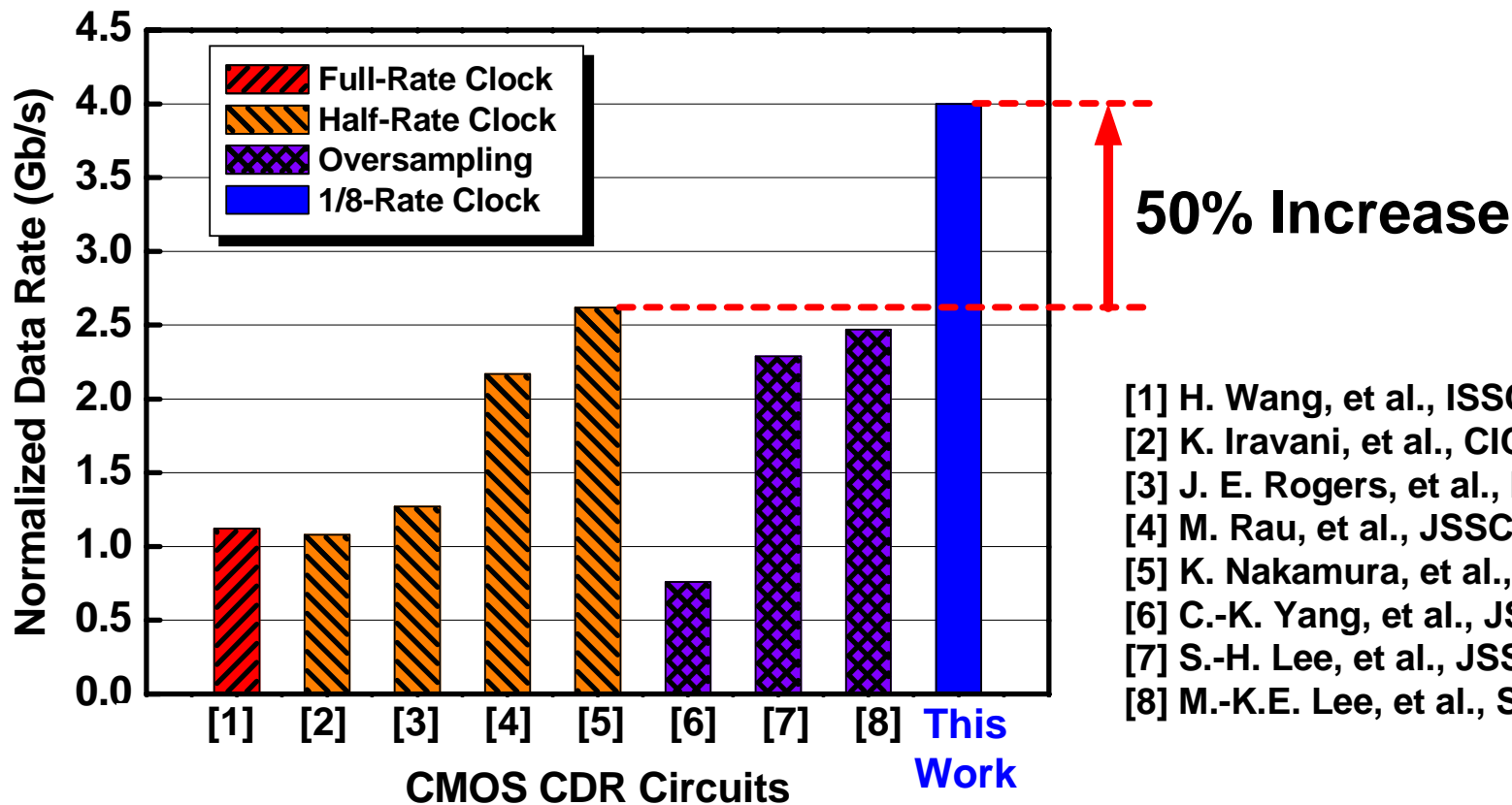
$$\text{Normalized Data Rate} = \left(\frac{\text{Technology}}{0.25 \mu\text{m}} \right) \cdot \left(\frac{70 \text{ mW}}{\text{Power Consumption}} \right) \cdot \left(\frac{\text{Supply Voltage}}{2.5 \text{ V}} \right) \times \text{Data Rate (Gb/s)}$$

Performance Comparison

Reference	CDR Technique	Normalized Data Rate	Data Rate	Power Consumption	Supply Voltage	Technology
[1]	Full-Rate Clock	1.12-Gb/s	1-Gb/s	300 mW	5 V	0.6- μ m CMOS
[2]	Half-Rate Clock	1.08-Gb/s	1.25-Gb/s	150 mW	3.3 V	0.35- μ m CMOS
[3]	Half-Rate Clock	1.27-Gb/s	10-Gb/s	285 mW	1.8 V	0.18- μ m CMOS
[4]	Half-Rate Clock	2.17-Gb/s	1-Gb/s	85 mW	3.3 V	0.5- μ m CMOS
[5]	Half-Rate Clock	2.62-Gb/s	6-Gb/s	83 mW	1.8 V	0.18- μ m CMOS
[6]	3x-Oversampling	0.76-Gb/s	4-Gb/s	973.5 mW	3.3 V	0.5- μ m CMOS
[7]	3x-Oversampling	2.29-Gb/s	5-Gb/s	153 mW	2.5 V	0.25- μ m CMOS
[8]	2x-Oversampling	2.47-Gb/s	4-Gb/s	84 mW	1.93 V	0.24- μ m CMOS
This Work	1/8-Rate Clock	4-Gb/s	4-Gb/s	70 mW	2.5 V	0.25- μ m CMOS

$$\text{Normalized Data Rate} = \left(\frac{\text{Technology}}{0.25 \mu\text{m}} \right) \cdot \left(\frac{70 \text{ mW}}{\text{Power Consumption}} \right) \cdot \left(\frac{\text{Supply Voltage}}{2.5 \text{ V}} \right) \times \text{Data Rate (Gb/s)}$$

Normalized Performance Comparison



- [1] H. Wang, et al., ISSCC, 1999
- [2] K. Iravani, et al., CICC, 1998
- [3] J. E. Rogers, et al., ISSCC, 2002
- [4] M. Rau, et al., JSSC, July 1997
- [5] K. Nakamura, et al., SOVC, 1998
- [6] C.-K. Yang, et al., JSSC, May 1998
- [7] S.-H. Lee, et al., JSSC, Dec. 2002
- [8] M.-K.E. Lee, et al., SOVC, 2002

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Conclusion

- ❑ **A high-speed and low-power CDR circuit** has been introduced :
 - ❑ Exploiting **1/8-rate clock technique**
 - ❑ Using a 0.25- μm standard CMOS technology
 - ❑ Single functional block merging clock recovery circuit, decision circuit, divider, and 1:4 DEMUX

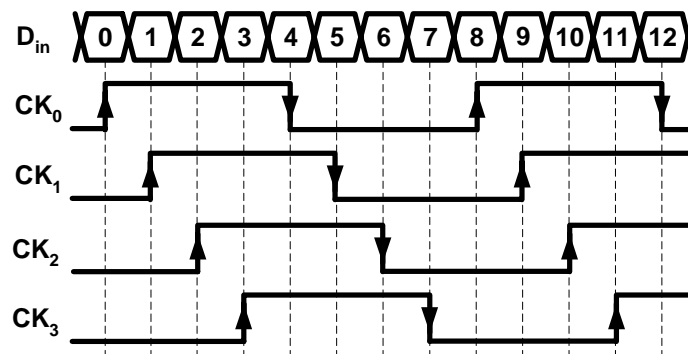
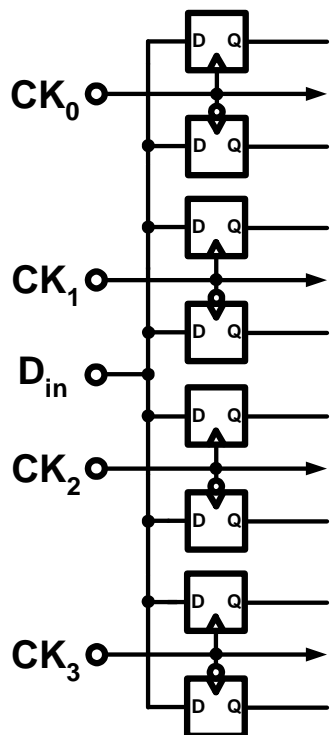
- ❑ The proposed CDR demonstrates **4-Gb/s** and **70mW** operation suitable for low cost optical interconnection applications.

Further Works

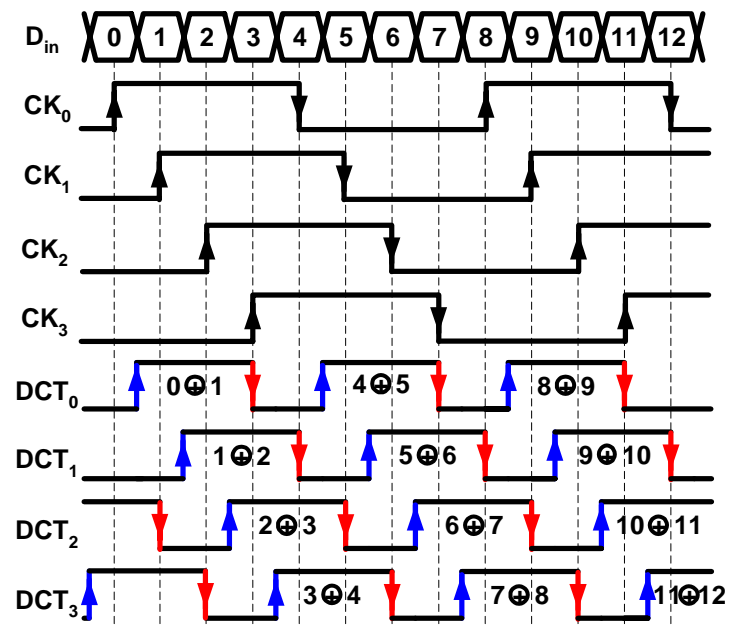
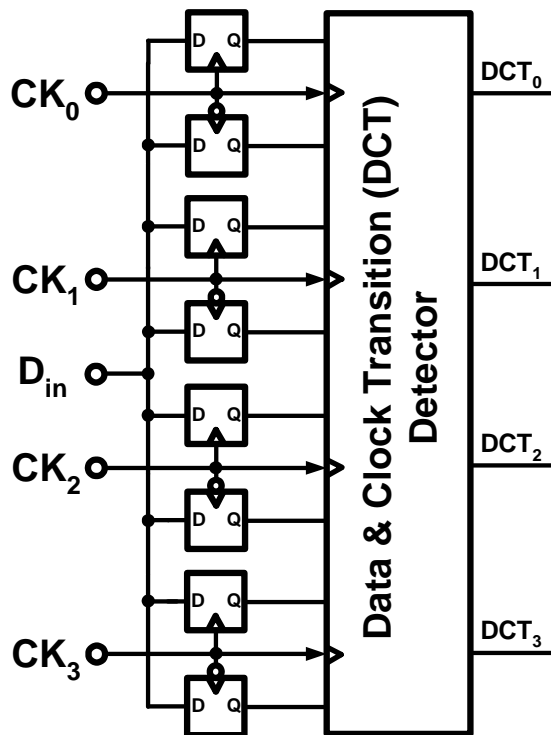
- Fully Integrated Frequency-Locked Loop**
 - Broadband frequency detection**
- Improvement of BER**
 - To improve SNR**
 - To improve Clock Jitter Characteristic**
- Need for Detailed Mathematical Analysis**

Supplemental Materials

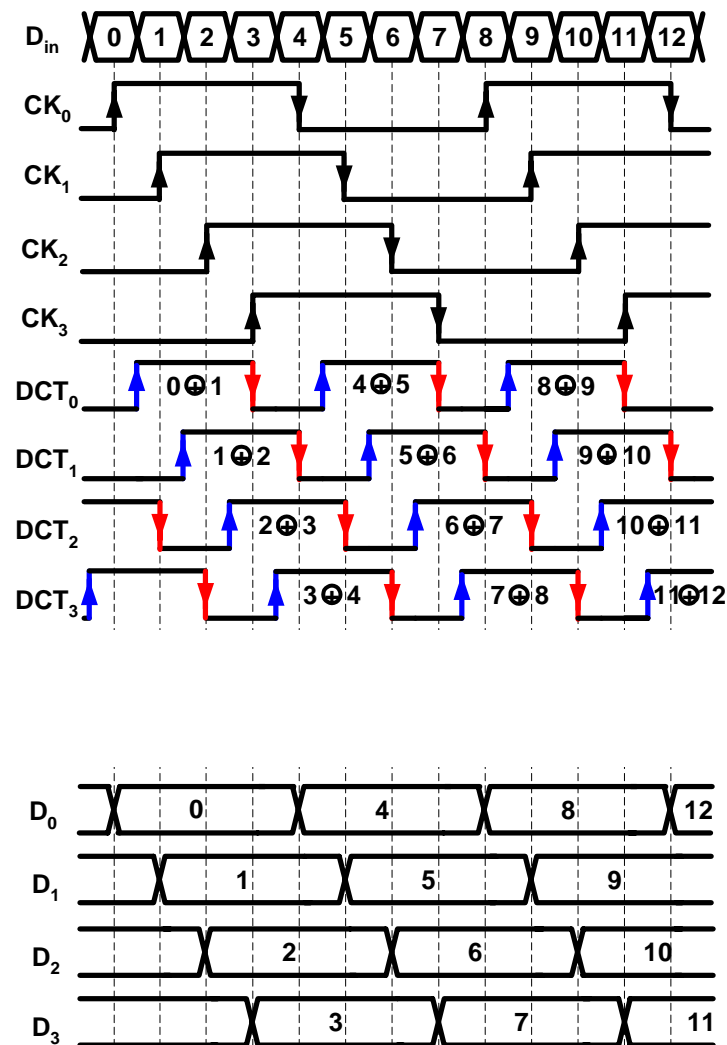
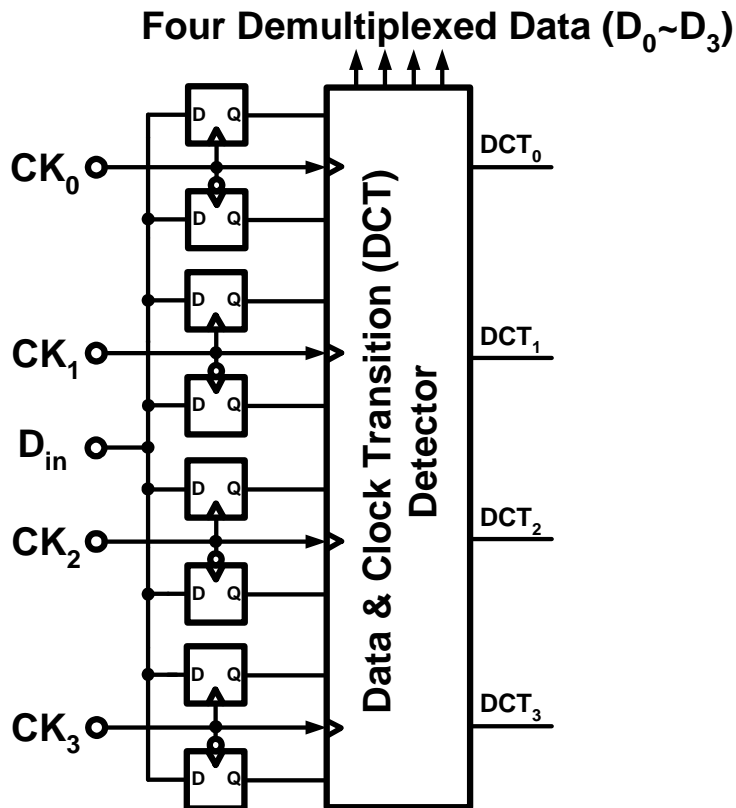
Operation of 1/8-Rate PD (1/4)



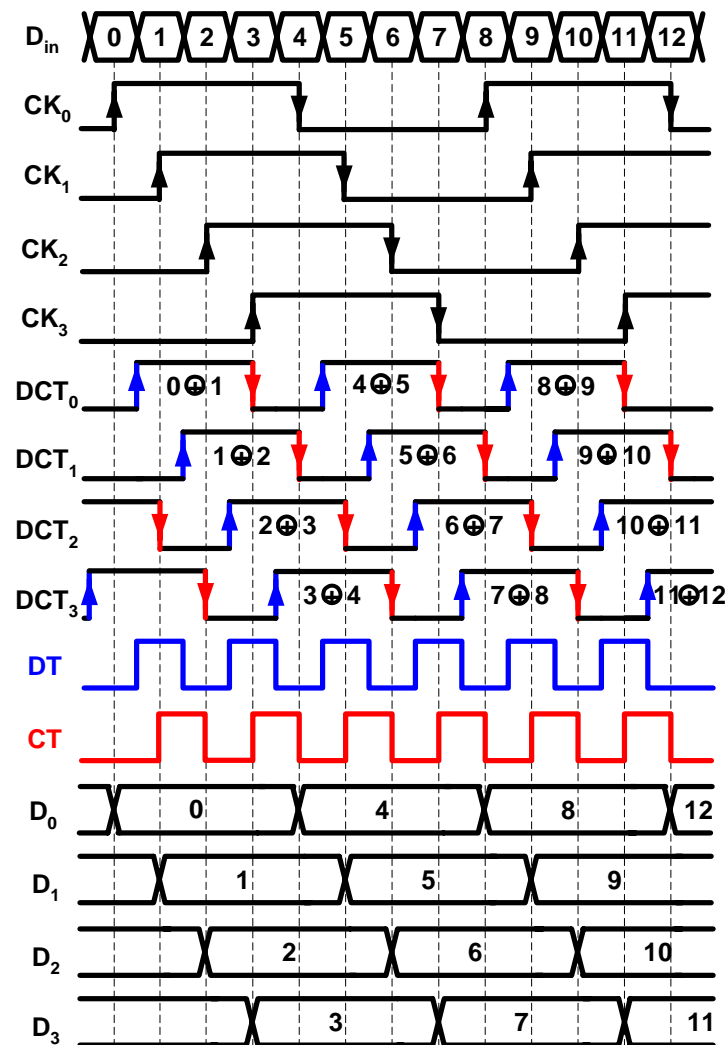
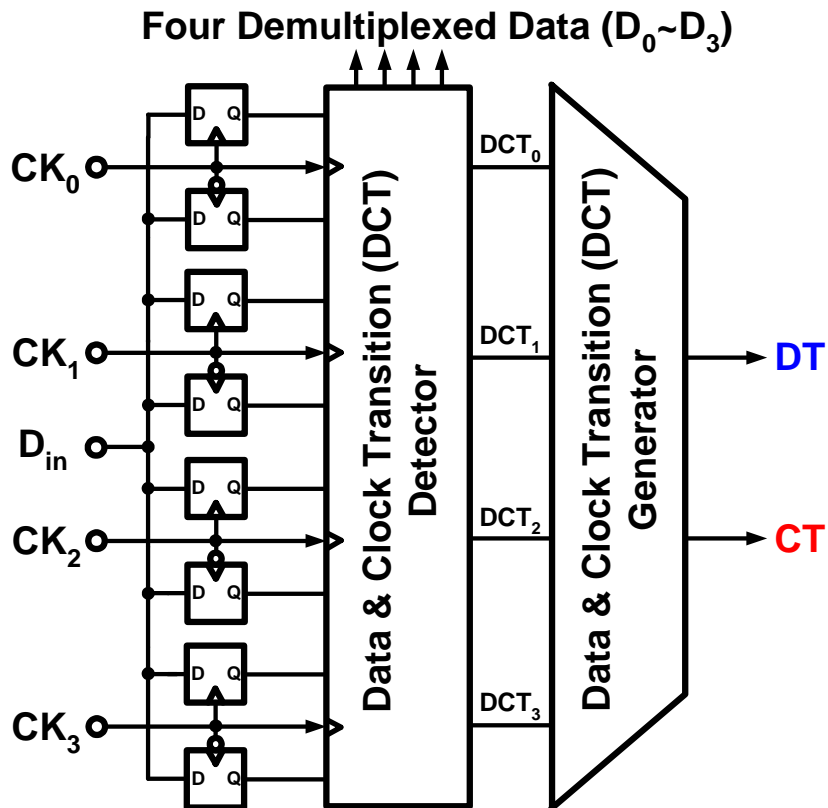
Operation of 1/8-Rate PD (2/4)



Operation of 1/8-Rate PD (3/4)



Operation of 1/8-Rate PD (4/4)



Example

